Network Security and Cryptography Applications

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Deadline for manuscript submissions:
31 July 2024

Message from the Guest Editors

Dear Colleagues,

Topics of interest include, but are not limited to, the following:

- Content-based network security;
- Industrial internet of things;
- AI-generated content security;
- Data security;
- Cryptography and its applications;
- Artificial intelligence security
- Blockchain-based data sharing across domains;
- Trusted data exchange;
- Cyberspace security;
- Knowledge representation and discovery;
- Intelligent systems;
- Data security and privacy;
- Deep learning algorithms and applications;
- Network attack and defense;
- Situation awareness;
- Machine learning

mdpi.com/si/188562

Special Issue

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Message from the Editor-in-Chief

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